

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
Reexamination
MEYER, JASON

Examiner

ALLEN CHAN

Art Unit

3714

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0190943 A1	10-2003	Walker et al.	463/17
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NON-PATENT DOCUMENTS

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